

# **HAF2012(L), HAF2012(S)**

# Silicon N Channel MOS FET Series Power Switching

REJ03G1139-0400 Rev.4.00 Jul 13, 2007

# **Description**

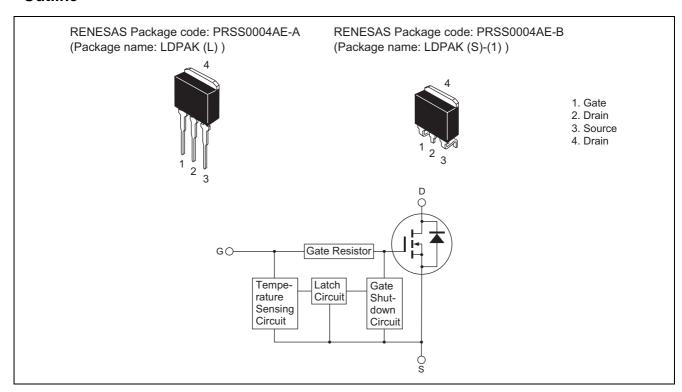
This FET has the over temperature shut-down capability sensing to the junction temperature.

This FET has the built-in over temperature shut-down circuit in the gate area. And this circuit operation to shut-down the gate voltage in case of high junction temperature like applying over power consumption, over current etc.

### **Features**

- Logic level operation (4 to 6 V Gate drive)
- High endurance capability against to the short circuit
- Built-in the over temperature shut-down circuit
- Latch type shut-down operation (Need 0 voltage recovery)

### **Outline**



# **Absolute Maximum Ratings**

 $(Ta = 25^{\circ}C)$ 

Item	Symbol	Value	Unit	
Drain to source voltage	V <sub>DSS</sub>	60	V	
Gate to source voltage	V <sub>GSS</sub>	16	V	
	V <sub>GSS</sub>	-2.8	V	
Drain current	I <sub>D</sub>	20	Α	
Drain peak current	I <sub>D (pulse)</sub> Note 1	40	Α	
Body-drain diode reverse drain current	I <sub>DR</sub>	20	Α	
Channel dissipation	Pch Note 2	50	W	
Channel temperature	Tch	150	°C	
Storage temperature	Tstg	-55 to +150	°C	

Notes: 1. PW  $\leq$  10  $\mu$ s, duty cycle  $\leq$  1%

2. Value at Ta = 25°C

# **Typical Operation Characteristics**

 $(Ta = 25^{\circ}C)$ 

Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Input voltage	V <sub>IH</sub>	3.5	_	_	V	
	V <sub>IL</sub>	_	_	1.2	V	
Input current	I <sub>IH1</sub>	_	_	100	μΑ	$Vi = 8 V, V_{DS} = 0$
(Gate non shut down)	I <sub>IH2</sub>	_	_	50	μΑ	$Vi = 3.5 V, V_{DS} = 0$
	I <sub>IL</sub>	_	_	1	μΑ	$Vi = 1.2 V, V_{DS} = 0$
Input current	I <sub>IH (sd) 1</sub>	_	0.8	_	mA	$Vi = 8 V, V_{DS} = 0$
(Gate shut down)	I <sub>IH (sd) 2</sub>	_	0.35	_	mA	$Vi = 3.5 V, V_{DS} = 0$
Shut down temperature	Tsd	_	175	_	°C	Channel temperature
Gate operation voltage	V <sub>OP</sub>	3.5		13	V	

# **Electrical Characteristics**

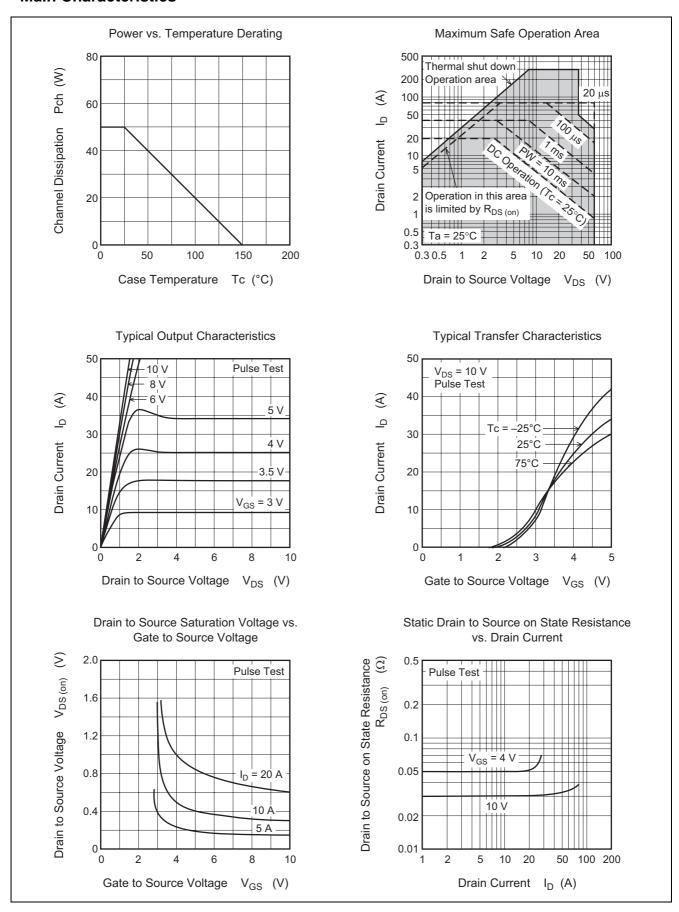
 $(Ta = 25^{\circ}C)$ 

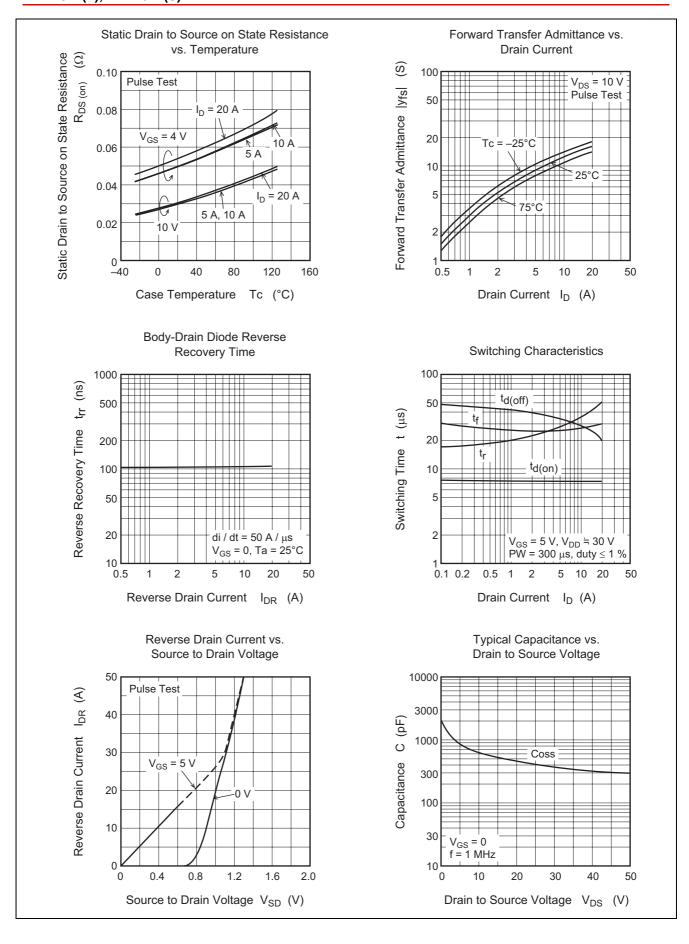
Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Drain current	I <sub>D1</sub>	10	_	_	Α	$V_{GS} = 3.5 \text{ V}, V_{DS} = 2 \text{ V}$
	I <sub>D2</sub>	_	_	10	mA	V <sub>GS</sub> = 1.2 V, V <sub>DS</sub> = 2 V
Drain to source breakdown voltage	V <sub>(BR) DSS</sub>	60	_	_	V	$I_D = 10 \text{ mA}, V_{GS} = 0$
Gate to source breakdown voltage	V (BR) GSS	16	_	_	V	$I_G = 100 \mu\text{A},  V_{DS} = 0$
	V (BR) GSS	-2.8	_	_	V	$I_G = -100 \mu\text{A},  V_{DS} = 0$
Gate to source leak current	I <sub>GSS1</sub>	_	_	100	μΑ	$V_{GS} = 8 \text{ V}, V_{DS} = 0$
	I <sub>GSS2</sub>	_	_	50	μΑ	$V_{GS} = 3.5 \text{ V}, V_{DS} = 0$
	I <sub>GSS3</sub>	_	_	1	μΑ	$V_{GS} = 1.2 \text{ V}, V_{DS} = 0$
	I <sub>GSS4</sub>	_	_	-100	μΑ	$V_{GS} = -2.4 \text{ V}, V_{DS} = 0$
Input current (shut down)	I <sub>GS (op) 1</sub>	_	0.8	_	mA	$V_{GS} = 8 \text{ V}, V_{DS} = 0$
	I <sub>GS (op) 2</sub>		0.35		mA	$V_{GS} = 3.5 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	I <sub>DSS</sub>	_	_	250	μΑ	$V_{DS} = 50 \text{ V}, V_{GS} = 0$
Gate to source cutoff voltage	V <sub>GS (off)</sub>	1.0	_	2.25	V	$I_D = 1 \text{ mA}, V_{DS} = 10 \text{ V}$
Static drain to source on state resistance	R <sub>DS (on)</sub>	_	50	65	mΩ	$I_D = 10 \text{ A}, V_{GS} = 4 \text{ V}^{\text{Note 3}}$
	R <sub>DS (on)</sub>	_	30	43	mΩ	$I_D = 10 \text{ A}, V_{GS} = 10 \text{ V}^{\text{Note 3}}$
Forward transfer admittance	y <sub>fs</sub>	6	12		Ø	$I_D = 10 \text{ A}, V_{DS} = 10 \text{ V}^{\text{Note 3}}$
Output capacitance	Coss	_	630	_	pF	$V_{DS} = 10 \text{ V}, V_{GS} = 0$
						f = 1 MHz
Turn-on delay time	t <sub>d (on)</sub>		7.5		μs	I <sub>D</sub> = 5 A
Rise time	t <sub>r</sub>		29		μs	$V_{GS} = 5 V$
Turn-off delay time	t <sub>d (off)</sub>	_	34	_	μs	$R_L = 6 \Omega$
Fall time	t <sub>f</sub>		26		μs	
Body-drain diode forward voltage	$V_{DF}$		1.0		V	$I_F = 20 \text{ A}, V_{GS} = 0$
Body-drain diode reverse recovery time	t <sub>rr</sub>		110	_	ns	I <sub>F</sub> = 20 A, V <sub>GS</sub> = 0
						$di_F/dt = 50 A/\mu s$
Over load shut down operation time Note4	t <sub>os1</sub>	_	1.8	_	ms	$V_{GS} = 5 \text{ V}, V_{DD} = 12 \text{ V}$
	t <sub>os2</sub>	_	0.7	_	ms	$V_{GS} = 5 \text{ V}, V_{DD} = 24 \text{ V}$

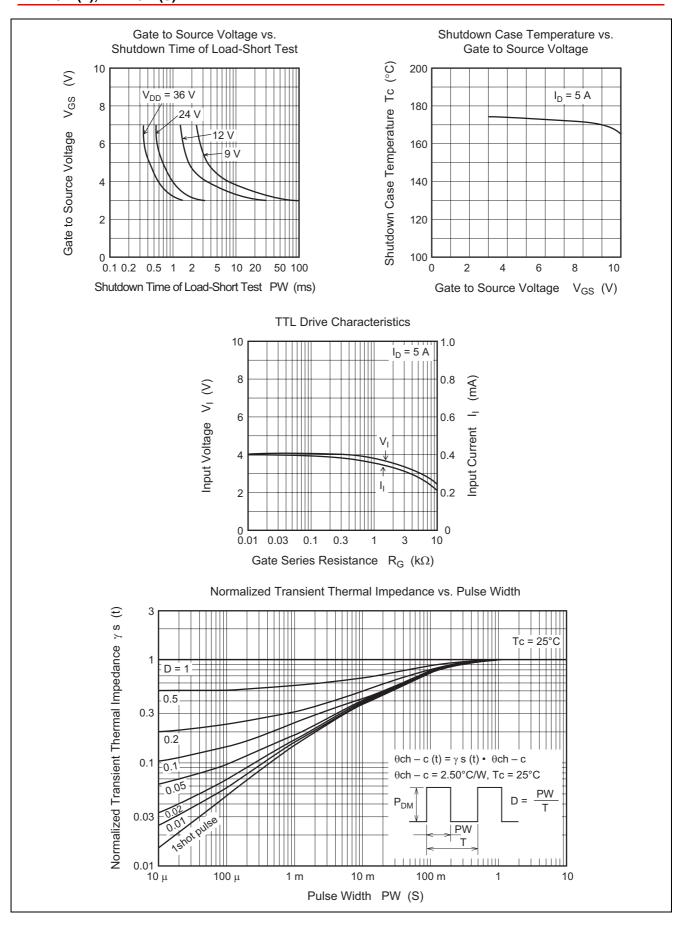
Notes: 3. Pulse test

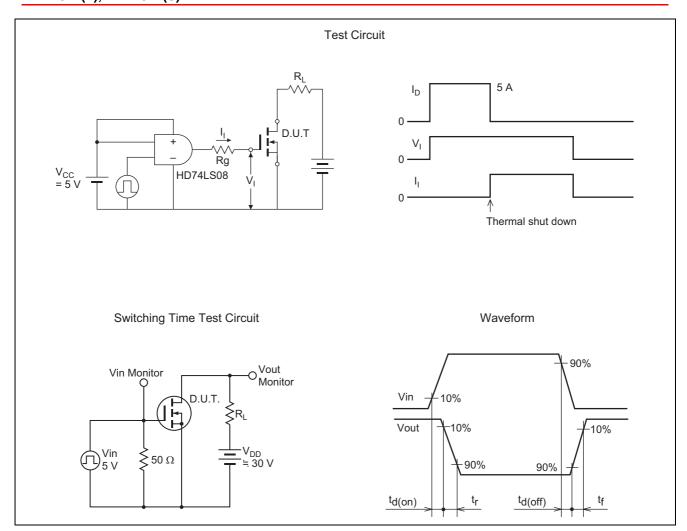
<sup>4.</sup> Including the junction temperature rise of the over loaded condition.

# **Main Characteristics**

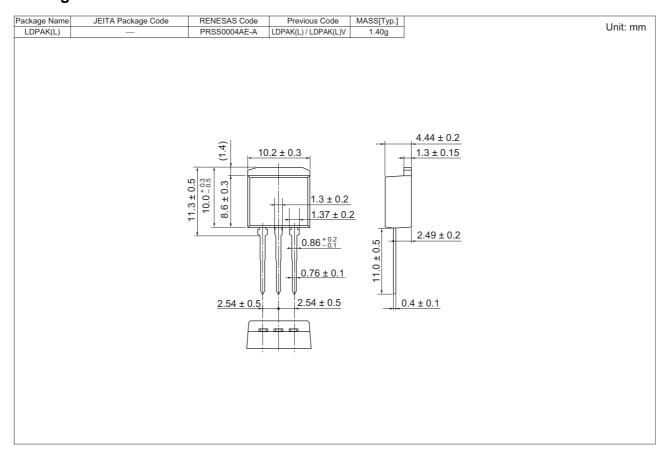


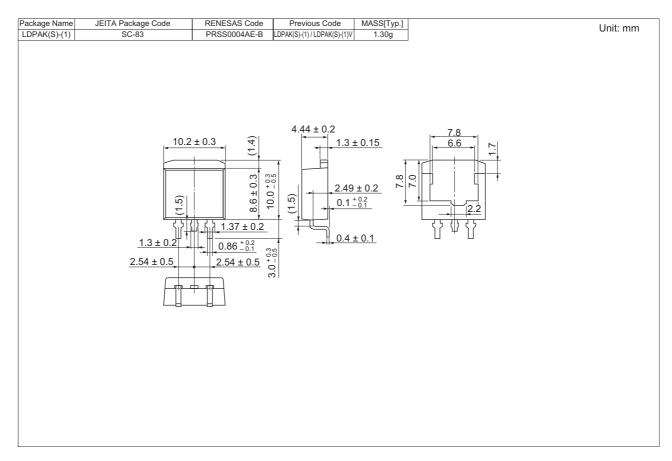






# **Package Dimensions**





# **Ordering Information**

Part Name	Quantity	Shipping Container
HAF2012-90L	Max: 50 pcs/sack	Sack
HAF2012-90S	Max: 50 pcs/sack	Sack
HAF2012-90STL	1000 pcs/Reel	Embossed tape
HAF2012-90STR	1000 pcs/Reel	Embossed tape

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